L Number	Hits	Search Text	DB	Time stamp
-	10	semiconductor and load near3 port near3 table	USPAT;	2003/01/29 09:56
	,		US-PGPUB;	
			EPO; JPO;	
			DERWENT	2003/01/29 09:56
-	4079	fuop	USPAT;	2003/01/29 09:56
			US-PGPUB; EPO; JPO;	
			DERWENT	
	24	semiconductor and fuop	USPAT;	2003/01/29 09:58
· .	27	Semiconductor and ruop	US-PGPUB;	2000,01,20 00.00
			EPO; JPO;	
			DERWENT	
-	· 229	semiconductor and foup	USPAT;	2003/01/29 10:08
			US-PGPUB;	
			EPO; JPO;	
			DERWENT	0000 (01 (00 10 00
-	5993	load near3 port	USPAT;	2003/01/29 10:09
- [US-PGPUB;	
		•	EPO; JPO; DERWENT	
	70	(semiconductor and foup) and (load near3 port)	USPAT;	2003/01/29 10:10
-	70	(Semiconductor and roup) and (load nears port)	US-PGPUB;	2003/01/23 10.10
			EPO; JPO;	
]			DERWENT	
_	2862706	(metrology or measuring or measure\$4 or	USPAT;	2003/01/29 16:54
		detect\$3).ab,ti.	US-PGPUB;	
			EPO; JPO;	
		•	DERWENT	
-	15	((semiconductor and foup) and (load near3 port))	USPAT;	2003/01/29 10:54
		and ((metrology or measuring or measure\$4 or	US-PGPUB;	
		detect\$3).ab,ti.)	EPO; JPO;	
		((and man) marth	DERWENT	2002/01/20 10:54
-	0	((semiconductor and foup) and (load near3 port))	USPAT; US-PGPUB;	2003/01/29 10:54
		and 76013920.uref,bi.	EPO; JPO;	
			DERWENT	
	12	6013920.uref,bi.	USPAT;	2003/01/29 16:16
	1-		US-PGPUB;	
:			EPO; JPO;	
			DERWENT	
-	1618	cluster near2 tool	USPAT;	2003/01/29 16:17
			US-PGPUB;	
			EPO; JPO;	
		(-1	DERWENT	2002/01/20 10:17
-	1354	(cluster near2 tool) and semiconductor	USPAT; US-PGPUB;	2003/01/29 16:17
	1		EPO; JPO;	
			DERWENT	
_	34	(cluster near2 tool) and load near2 port	USPAT;	2003/01/29 16:53
	34	(arabica menta took min tout menta port	US-PGPUB;	=,,,,
			EPO; JPO;	
		·	DERWENT	
-	2778	414/935-941.ccls.	USPAT;	2003/01/29 16:54
			US-PGPUB;	
			EPO; JPO;	
			DERWENT	0000 /01 /05 17 5
-	402	(metrology or measuring or measure\$4 or	USPAT;	2003/01/29 17:04
		detect\$3).ab,ti. and 414/935-941.ccls.	US-PGPUB;	
			EPO; JPO; DERWENT	
	31	((metrology or measuring or measure\$4 or	USPAT;	2003/01/29 17:18
-	31	detect\$3).ab,ti. and 414/935-941.ccls.) and seal\$3	US-PGPUB;	2003/01/23 17.10
9		and environment	EPO; JPO;	
		, , ,	DERWENT	
	2 /2 /22	3·30·29 PM Page 1	<u> </u>	

-	13	metrology same semiconductor same load	USPAT;	2003/01/29 17:19
			US-PGPUB;	
		•	EPO; JPO;	
	1		DERWENT	